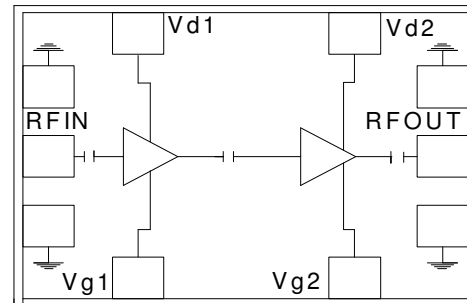


## 11 - 15 GHz 0.5 Watt Power Amplifier

### Features

- ◆ Frequency Range : 11 - 15GHz
- ◆ 27.5 dBm output Psat
- ◆ 13 dB Power gain
- ◆ 25% PAE
- ◆ High IP3
- ◆ Input Return Loss > 11 dB
- ◆ Output Return Loss > 6 dB
- ◆ Dual bias operation
- ◆ No external matching required
- ◆ DC decoupled input and output
- ◆ 0.15  $\mu\text{m}$  InGaAs pHEMT Technology
- ◆ Chip dimension: 2.4 x 1.7 x 0.1 mm

Functional Diagram



### Typical Applications

- ◆ RADAR
- ◆ Military & space
- ◆ LMDS, VSAT

### Description

The AMT2153021 is a Ku-band Power amplifier with 0.5 watt power output. The PA uses 2 stages of amplification and operates in 11 - 15 GHz frequency range. The PA features 13 dB of gain with input and output return losses of 11 dB and 6 dB respectively. The PA has a high IP3 of 36dBm and 25% PAE. The chip operates with dual bias supply voltage. The die is fabricated using a reliable 0.15 $\mu\text{m}$  InGaAs pHEMT technology. The Circuit grounds are provided through vias to the backside metallization.

### Absolute Maximum Ratings <sup>(1)</sup>

Parameter	Absolute Maximum	Units
Drain bias voltage (Vd)	+6	volts
Drain current (Idq)	500	mA
RF input power (RFIn at Vd=9V)	23	dBm
Operating temperature	-50 to +85	°C
Storage Temperature	-65 to +150	°C

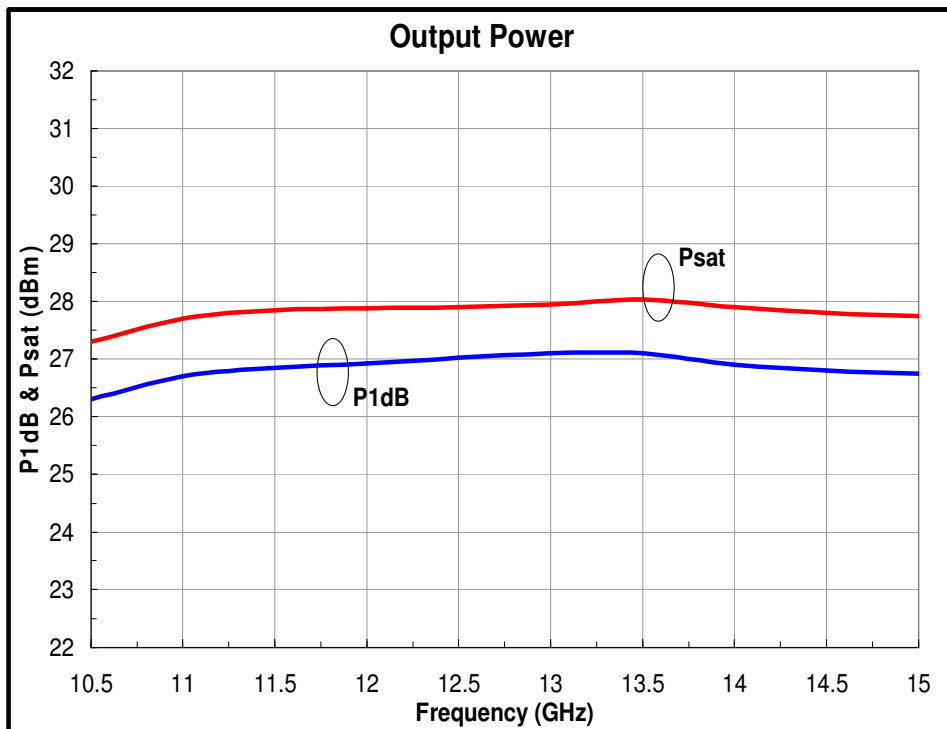
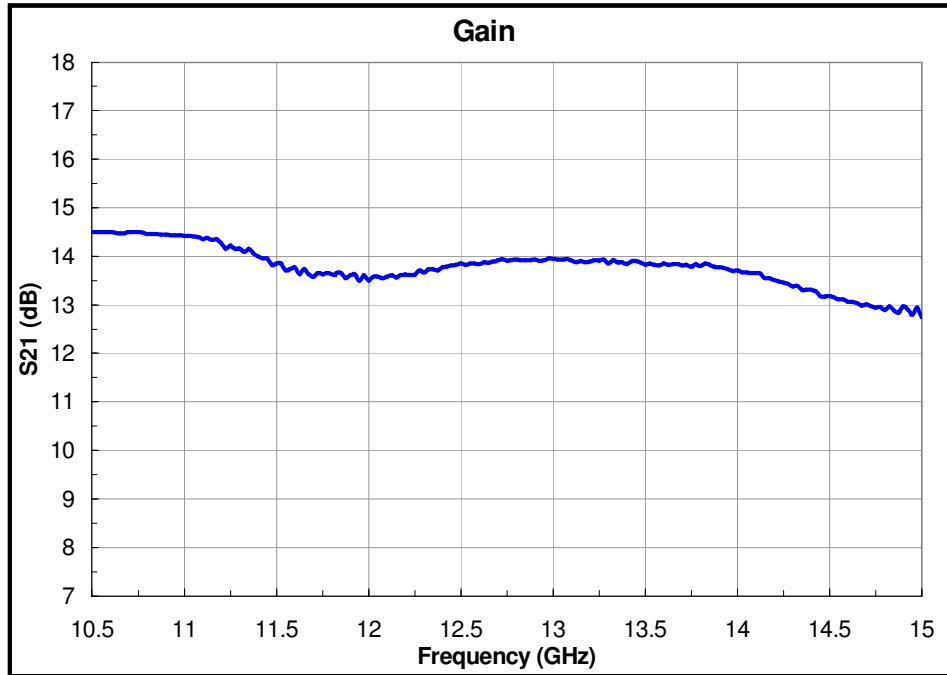
1. Operation beyond these limits may cause permanent damage to the component

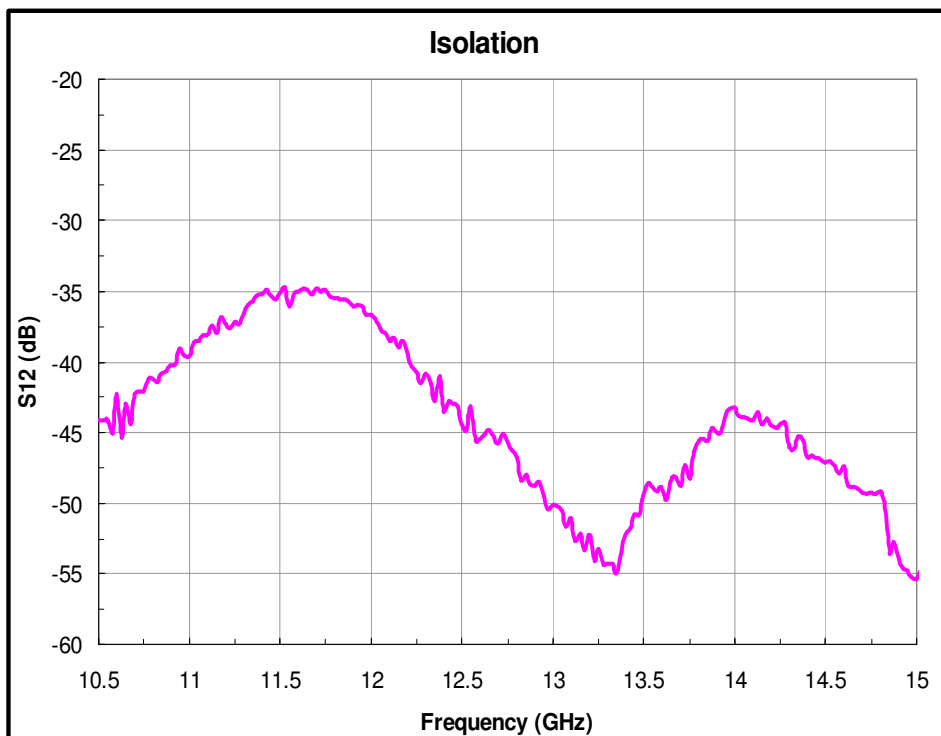
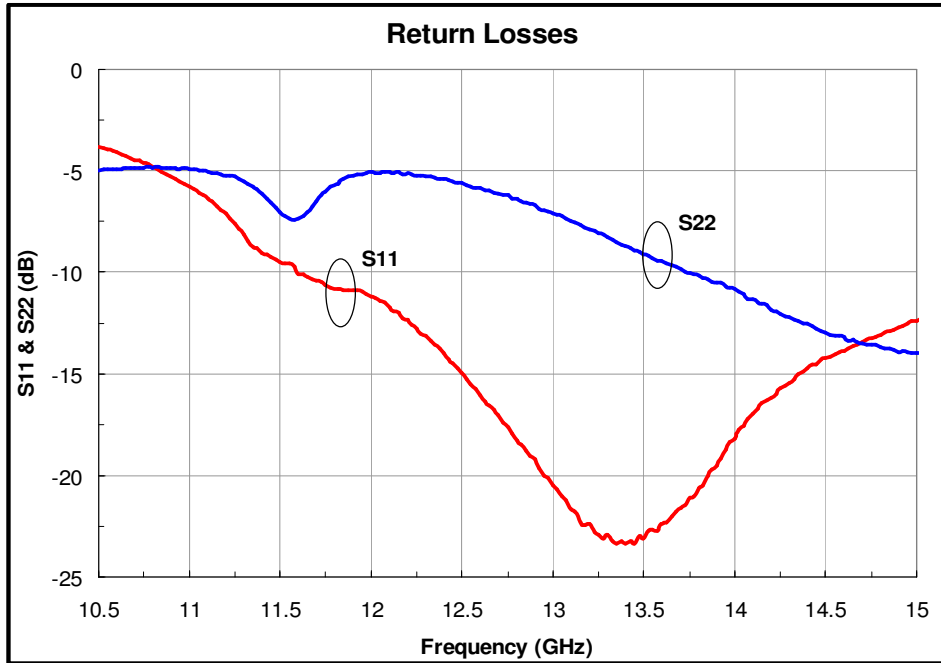
**Electrical Specifications <sup>(1)</sup> @ T<sub>A</sub> = 25 °C, V<sub>d1</sub> = V<sub>d2</sub> = 5V, V<sub>g1</sub> = V<sub>g2</sub> = -0.65V  
Z<sub>o</sub> = 50 Ω**

Parameter	Typ.	Units
Frequency Range	11 - 15	GHz
Gain	13	dB
Gain Flatness	+/-0.6	dB
Output Power (P1 dB)	26.5	dBm
Input Return Loss	11	dB
Output Return Loss	6	dB
Saturated output power (P <sub>sat</sub> )	27.5	dBm
Output Third Order Intercept (IP3)	36	dBm
Power Added Efficiency (PAE)	25%	--
Supply Current (I <sub>dq</sub> )	300	mA
Saturated current (I <sub>dsat</sub> ) <sup>2</sup>	500	mA

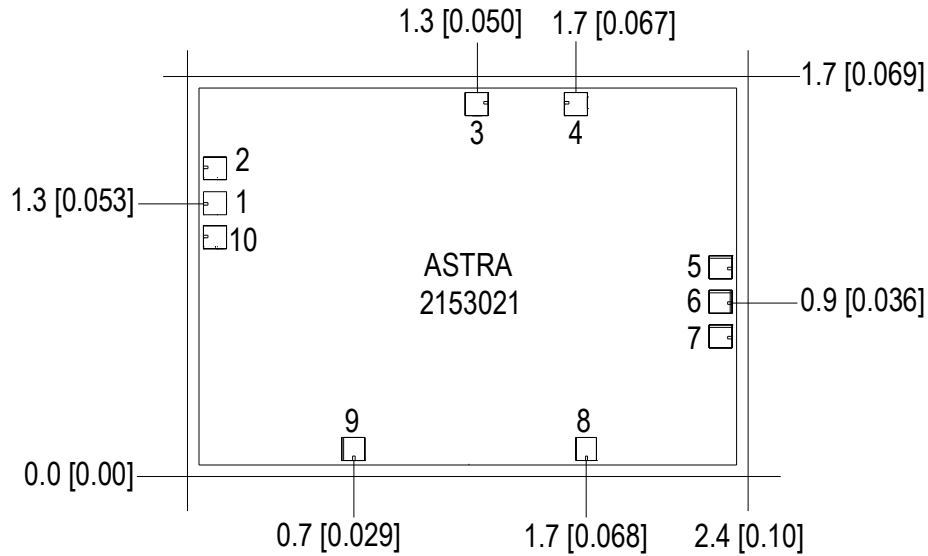
**Note:**

1. Electrical specifications as measured in test fixture.
2. Operating current is between I<sub>dq</sub> and I<sub>dsat</sub>.

**Test fixture data**
 $V_{d1} = V_{d2} = 5V, V_{g1} = V_{g2} = -0.65V, \text{Total Current } (I_{dq}) = 300mA, T_A = 25^\circ C$ 


**Test fixture data**
 $V_{d1} = V_{d2} = 5V, V_{g1} = V_{g2} = -0.65V, \text{Total Current } (I_{dq}) = 300mA, T_A = 25^\circ C$ 


## Bond Pad Locations

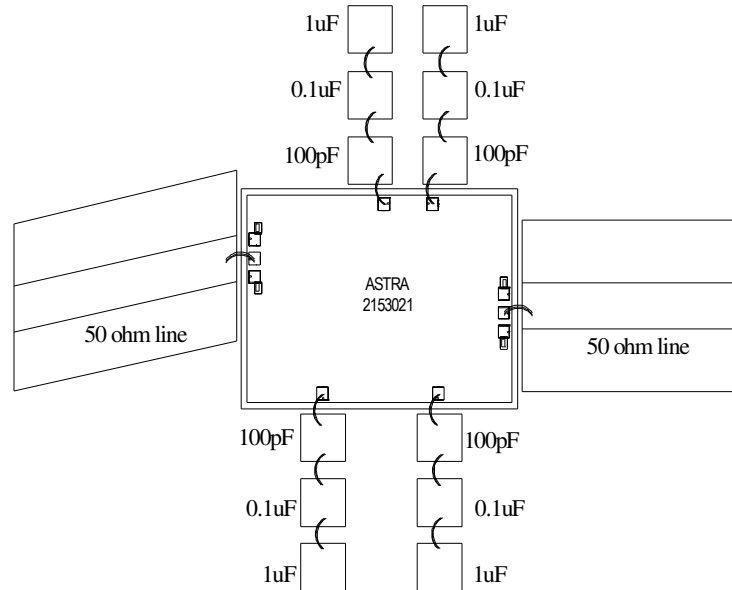


**Units:** millimeters (inches)

**Note:**

1. All RF and DC bond pads are 100 $\mu$ m x 100 $\mu$ m
2. Pad no. 1 : RF IN
3. Pad no. 3 : 1st stage drain voltage( $V_{d1}$ )
4. Pad no. 6 : RF Out
5. Pad no. 4 : 2nd stage drain voltage( $V_{d2}$ )
6. Pad no. 8 : 2<sup>nd</sup> stage gate voltage( $V_{g2}$ )
7. Pad no. 9 : 1<sup>st</sup> stage gate voltage ( $V_{g1}$ )

## Recommended Assembly Diagram



### Note :

1. Two 1 mil (0.0254mm) bond wires of minimum length should be used for RF input and output.
2. Two 1 mil (0.0254mm) bond wires of minimum length should be used from chip bond pad to 100pF capacitor.
3. Input and output 50 ohm lines are on 5 mil RT Duroid substrate
4. 0.1  $\mu\text{F}$  capacitors may be additionally used as a second level of bypass for reliable operation
5. The RF input & output ports are DC decoupled on-chip.
6. Proper heat sink like Copper tungsten or copper molybdenum to be used for better reliability of chip

**Die attach:** For Epoxy attachment, use of a two-component conductive epoxy is recommended. An epoxy fillet should be visible around the total die periphery. If Eutectic attachment is preferred, use of fluxless AuSn (80/20) 1-2 mil thick preform solder is recommended. Use of AuGe preform should be strictly avoided.

**Wire bonding:** For DC pad connections use either ball or wedge bonds. For best RF performance, use of 150 - 200 $\mu\text{m}$  length of wedge bonds is advised. Single Ball bonds of 250-300 $\mu\text{m}$  though acceptable, may cause a deviation in RF performance.



***GaAs MMIC devices are susceptible to Electrostatic discharge. Proper precautions should be observed during handling, assembly & testing***

All information and Specifications are subject to change without prior notice